

Search Notes

Application/Control No.

10/762,745

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under
Reexamination

YOSHIDA ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	1	6/14/2008	YB
709	206		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Int. Search		6/14/2008	YB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Int.+Fwd/Bwd	6/14/2008	YB